**Product data sheet** 

## 1. General description

WG30N65HAW1 uses advanced Fine Trench Field-stop IGBT technology with antiparallel diode in TO247 package to provide extremely low  $V_{\text{CE(sat)}}$ , and excellent switching performance. This device offers Best-in-Class efficiency in hard switching and resonant topology.



### 2. Features and benefits

- · Maximum junction temperature 175 °C
- · Positive Temperature efficient for easy paralleling
- · Very soft, fast recovery anti-parallel diode
- · High switching speed
- · EMI Improved Design

## 3. Applications

- PFC
- Solar converters
- UPS
- Welding Converters
- · Mid to high range switching frequency converters

### 4. Quick reference data

#### Table 1. Quick reference data

Symbol	Parameter			Value			Unit	
V <sub>CE</sub>	Collector-emitter voltage, T <sub>j</sub> ≥ 25 °C			650			V	
I <sub>C</sub>	DC collector current, limited by $T_{j(max)}$ $T_C = 100  ^{\circ}C$				30		Α	
Symbol	Parameter Conditions		Notes	Min	Тур	Max	Unit	
Static cha	Static characteristics							
V <sub>CE(sat)</sub>	Collector-emitter saturation voltage	$V_{GE} = 15 \text{ V}; I_{C} = 30 \text{ A}; T_{j} = 25 ^{\circ}\text{C}$		-	1.55	2.1	V	

# 5. Pinning information

## **Table 2. Pinning information**

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		•C
2	С	collector		
3	Е	emitter		
mb	С	mounting base; connected to collector	TO247	G E sym200

# 6. Ordering information

## **Table 3. Ordering information**

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
WG30N65HAW1	TO247	WG30N65HAW1Q	Tube	30	SOT429	25-Mar-2013

# 7. Marking

#### **Table 4. Marking codes**

Type number	Marking codes
WG30N65HAW1	G30N65 HAW1

# 8. Limiting values

### Table 5. Limiting values

Symbol	Parameter	Notes	Value	Unit
$V_{CE}$	Collector-emitter voltage, T <sub>j</sub> ≥ 25 °C		650	V
I <sub>C</sub>	DC collector current, limited by $T_{j(max)}$ $T_{c}$ = 25 °C $T_{c}$ = 100 °C		60 30	A
I <sub>C(puls)</sub>	Pulsed collector current, t <sub>p</sub> limited by T <sub>j(max)</sub>		90	Α
-	Turn off safe operating area $V_{CE} \le 650 \text{ V}, T_j \le 175 ^{\circ}\text{C}, t_p = 1  \mu\text{s}$		90	А
l <sub>F</sub>	Diode forward current, limited by $T_{j(max)}$ $T_{C}$ = 25 °C $T_{C}$ = 100 °C		20 10	А
I <sub>Fpuls</sub>	Diode pulsed current, t <sub>p</sub> limited by T <sub>j(max)</sub>		30	Α
$V_{\sf GE}$	Gate-emitter voltage		±20	V
P <sub>tot</sub>	Power dissipation $T_C = 25 ^{\circ}\text{C}$ Power dissipation $T_C = 100 ^{\circ}\text{C}$		312 156	W
T <sub>stg</sub>	Storage temperature		-55 to +150	°C
T <sub>jmax</sub>	Maximum operating junction temperature		175	°C
-	Peak soldering temperture		260	°C
М	Mounting Torque with washer		0.55	Nm

## 9. Thermal characteristics

**Table 6. Thermal characteristics** 

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R <sub>th(j-c)</sub>	IGBT thermal resistance from junction to case			-	0.48	-	K/W
R <sub>th(j-c)</sub>	Diode thermal resistance from junction to case			-	2	-	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient			-	40	-	K/W

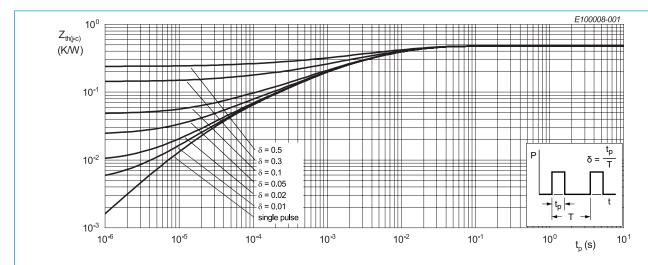


Fig. 1. Transient thermal impedance from junction to case as a function of pulse duration; IGBT

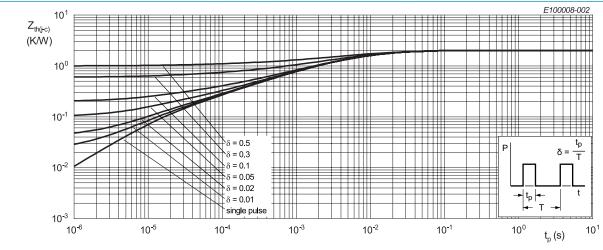


Fig. 2. Transient thermal impedance from junction to case as a function of pulse duration; Diode

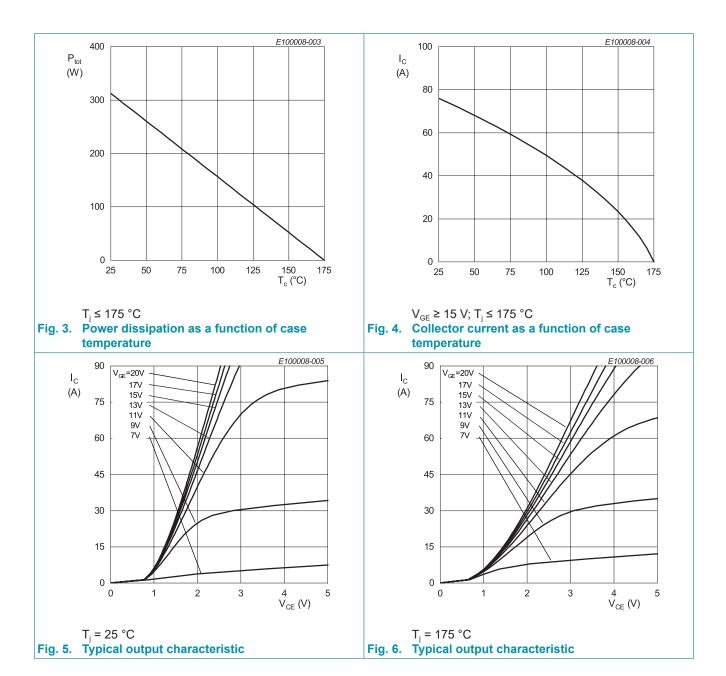
## 10. Characteristics

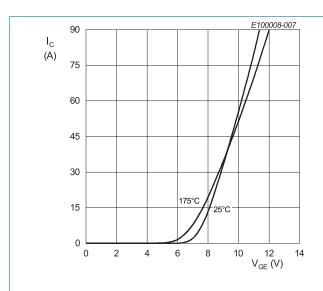
#### Table 7. Characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static cha	racteristics						
BV <sub>CES</sub>	Collector-emitter breakdown voltage	$V_{GE} = 0 \text{ V; } I_{C} = 1.0 \text{ mA}$		650	-	-	V
$V_{\text{CE(sat)}}$	Collector-emitter saturation	$V_{GE} = 15 \text{ V}; I_{C} = 30 \text{ A}; T_{j} = 25 \text{ °C}$		-	1.55	2.1	V
	voltage	$V_{GE}$ = 15 V; $I_{C}$ = 30 A; $T_{j}$ = 175 °C		-	2.05	-	V
$V_{F}$	Diode forward voltage	$V_{GE} = 0 \text{ V}; I_F = 10 \text{ A}; T_j = 25 ^{\circ}\text{C}$		-	1.9	-	V
		V <sub>GE</sub> = 0 V; I <sub>F</sub> = 10 A; T <sub>j</sub> = 175 °C		-	1.45	-	V
$V_{\text{GE(th)}}$	Gate-emitter threhold voltage	$I_{\rm C}$ = 0.6 mA; $V_{\rm CE}$ = $V_{\rm GE}$		4.3	5.4	6.5	V
I <sub>CES</sub>	Zero gate voltage collector current	$V_{CE} = 650 \text{ V}; V_{GE} = 0 \text{ V}; T_j = 25 \text{ °C}$		-	-	100	μA
		$V_{CE} = 650 \text{ V}; V_{GE} = 0 \text{ V}; T_j = 175 ^{\circ}\text{C}$		-	-	1	mA
g <sub>fs</sub>	Transconductance	V <sub>CE</sub> = 20 V; I <sub>C</sub> = 30 A		-	21	-	S
Dynamic	characteristics						
C <sub>ies</sub>	Input capacitance	$V_{CE} = 30 \text{ V}; V_{GE} = 0 \text{ V}; f = 1 \text{ MHz};$		-	1593	-	pF
C <sub>oes</sub>	Output capacitance	T <sub>j</sub> = 25 °C		-	45	-	pF
C <sub>res</sub>	Reverse transfer capacitance	rerse transfer capacitance		-	18	-	pF
$Q_{G}$	Gate charge	$V_{CC}$ = 520 V; $I_{C}$ = 30 A; $V_{GE}$ = 15 V; $T_{j}$ = 25 °C		-	74	-	nC

# 11. Switching Characteristics

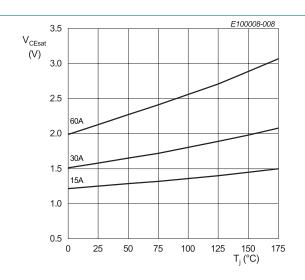
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
IGBT cha	racteristics						
$t_{d(on)}$	Turn-on delay time	T <sub>j</sub> = 25 °C;		-	30	-	nS
t <sub>r</sub>	Rise time	$V_{CC} = 400 \text{ V}; I_C = 30 \text{ A}; V_{GE} = 15 \text{V} / 0 \text{V};$ $R_G = 10 \Omega$		-	33	-	nS
$t_{d(off)}$	Turn-off delay time			-	120	-	nS
t <sub>f</sub>	Fall time			-	23	-	nS
E <sub>on</sub>	Turn-on energy			-	0.6	-	mJ
E <sub>off</sub>	Turn-off energy			-	0.3	-	mJ
E <sub>ts</sub>	Total switching energy			-	0.9	-	mJ
t <sub>d(on)</sub>	Turn-on delay time	$T_{j} = 175 ^{\circ}\text{C};$ $V_{CC} = 400 \text{V};  I_{C} = 30 \text{A};  V_{GE} = 15 \text{V} / 0 \text{V};$ $R_{G} = 10 \Omega$		-	29	-	nS
t <sub>r</sub>	Rise time			-	33	-	nS
$t_{d(off)}$	Turn-off delay time			-	143	-	nS
t <sub>f</sub>	Fall time			-	38	-	nS
E <sub>on</sub>	Turn-on energy			-	0.9	-	mJ
E <sub>off</sub>	Turn-off energy			-	0.45	-	mJ
E <sub>ts</sub>	Total switching energy			-	1.35	-	mJ
Diode cha	aracteristics						
t <sub>rr</sub>	Reverse recovery time	T <sub>j</sub> = 25 °C;		-	32	-	nS
Q <sub>r</sub>	Reverse recovery charge	$\dot{V}_R = 400 \text{ V}; I_F = 10 \text{ A}; dI_F/dt = 500 \text{A/us}$		-	148	-	nC
I <sub>RM</sub>	Reverse recovery peak current			-	8	-	А
t <sub>rr</sub>	Reverse recovery time	T <sub>j</sub> = 175 °C; V <sub>R</sub> = 400 V; I <sub>F</sub> = 10 A; dI <sub>F</sub> /dt = 500A/us		-	71	-	nS
Q <sub>r</sub>	Reverse recovery charge			-	508	-	nC
I <sub>RM</sub>	Reverse recovery peak current			-	12	-	А





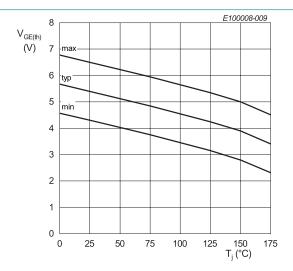
 $V_{CE} = 20 \text{ V}$ 

Fig. 7. Typical transfer characteristic



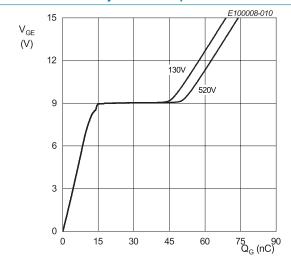
 $V_{GE} = 15 V$ 

Fig. 8. Typical collector-emitter saturation voltage as a function of junction temperature



 $I_{\rm C} = 600 \ \mu A$ 

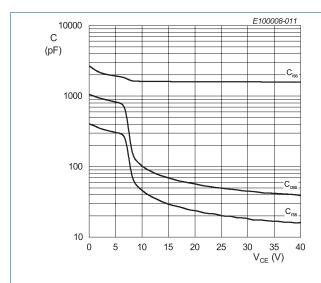
Fig. 9. Gate-emitter threshold voltage as a function of junction temperature

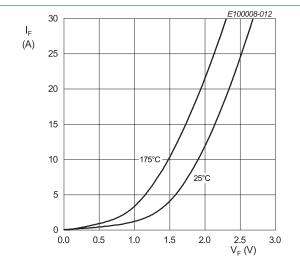


 $I_{c} = 30 \text{ A}$ 

Fig. 10. Typical gate charge

**Product data sheet** 

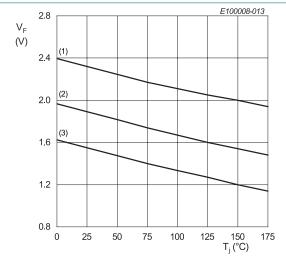


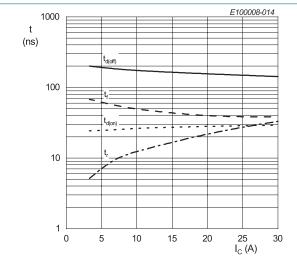


 $V_{GE} = 0 \text{ V}; f = 1 \text{ MHz}$ 

Fig. 11. Typical capacitance as a function of collector-emitter voltage

Fig. 12. Typical diode forward current as a function of forward voltage



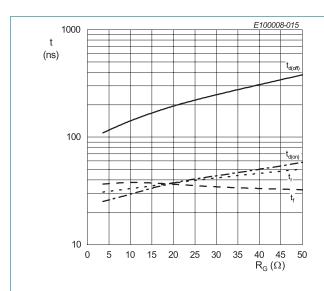


(1)  $I_F = 20 \text{ A}$ (2)  $I_F = 10 \text{ A}$ 

(3)  $I_F = 5 A$ 

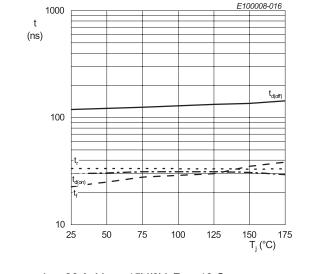
 $R_g$  = 10  $\Omega$ ;  $V_{GE}$  = 15V/0V;  $T_j$  = 175 °C;  $V_{CE}$  = 400 V; inductive load Fig. 14. Typical switching times as a function of collector current





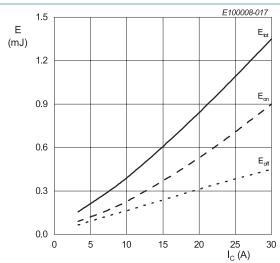
 $I_C$  = 30 A;  $V_{GE}$  = 15V/0V;  $T_j$  = 175 °C;  $V_{CE}$  = 400 V; inductive load

Fig. 15. Typical switching times as a function of gate resistance



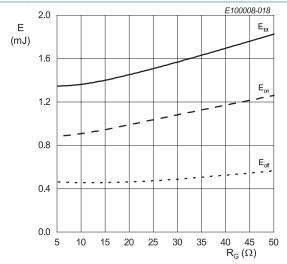
 $I_{C}$  = 30 A;  $V_{GE}$  = 15V/0V;  $R_{g}$  = 10  $\Omega$ ;  $V_{CE}$  = 400 V; inductive load

Fig. 16. Typical switching times as a function of junction temperature



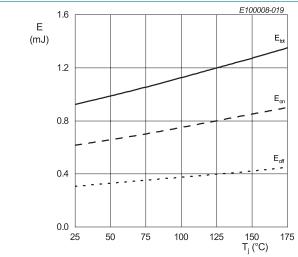
 $R_g = 10 \Omega$ ;  $V_{GE} = 15V/0V$ ;  $T_j = 175 ^{\circ}C$ ;  $V_{CE} = 400 V$ ; inductive load

Fig. 17. Typical switching energy losses as a function of collector current



 $I_{\text{C}}$  = 30 A;  $V_{\text{GE}}$  = 15V/0V;  $T_{j}$  = 175 °C;  $V_{\text{CE}}$  = 400 V; inductive load

Fig. 18. Typical switching energy losses as a function of gate resistance



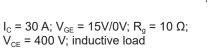


Fig. 20. Forward bias safe operating area



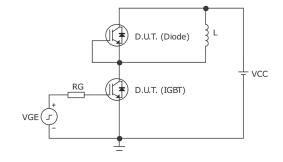


Fig. 21. Test circuit for inductive load switching

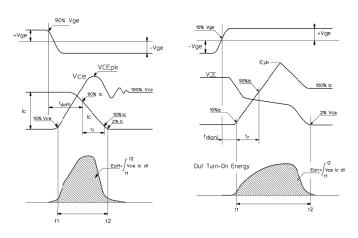
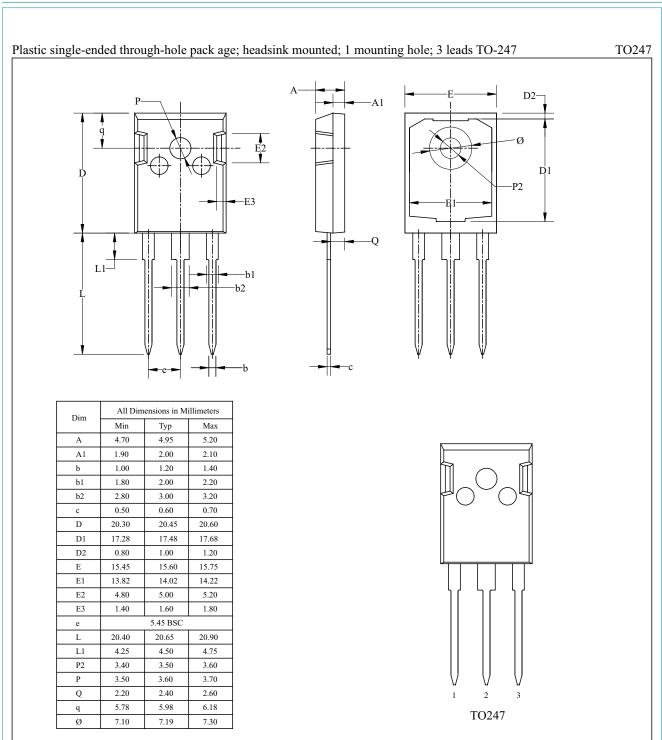


Fig. 22. Definition of switching times and losses

# 12. Package outline



**Product data sheet** 

**IGBT** 

## 13. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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